Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination	7
10/735,844	TAKEHARA ET AL.	
Examiner	Art Unit	
Alvin T. Raetzsch	1754	

	SEAR	CHED	
Class	Subclass	Date	Examiner
423	445B	7/27/2006	ATR
	461	7/27/2006	ATR
977	845	7/29/2006	ATR
95	280	7/29/2006	ATR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
inventor name	7/11/2000	5 ATR
Google Scholar	7/27/2000	6 ATR
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